

Quantitative Study of High Dynamic Range Image Sensor Architectures

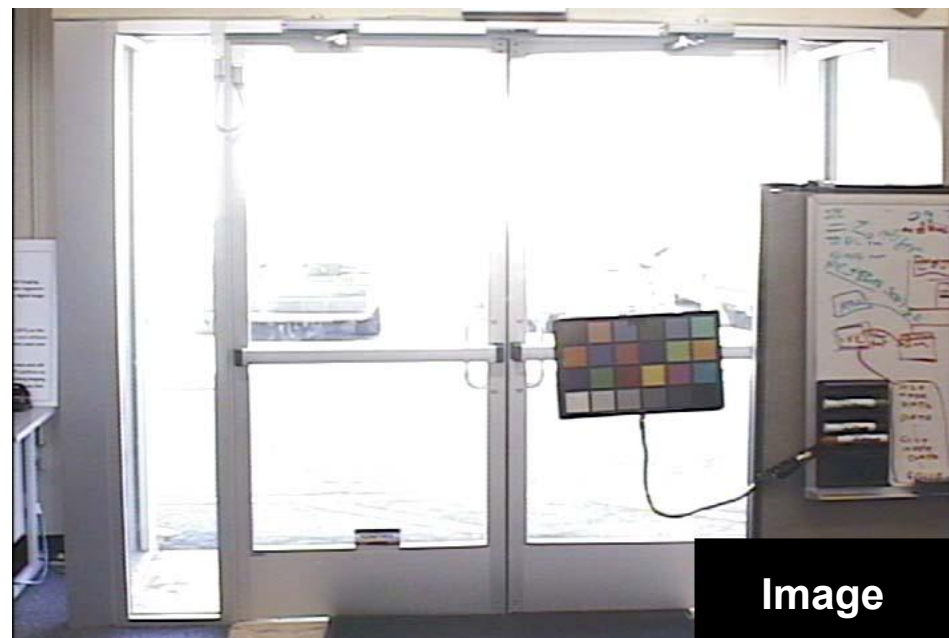
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Scene DR > Image Sensor DR



Courtesy Pixim Corporation

DR Extension Methods

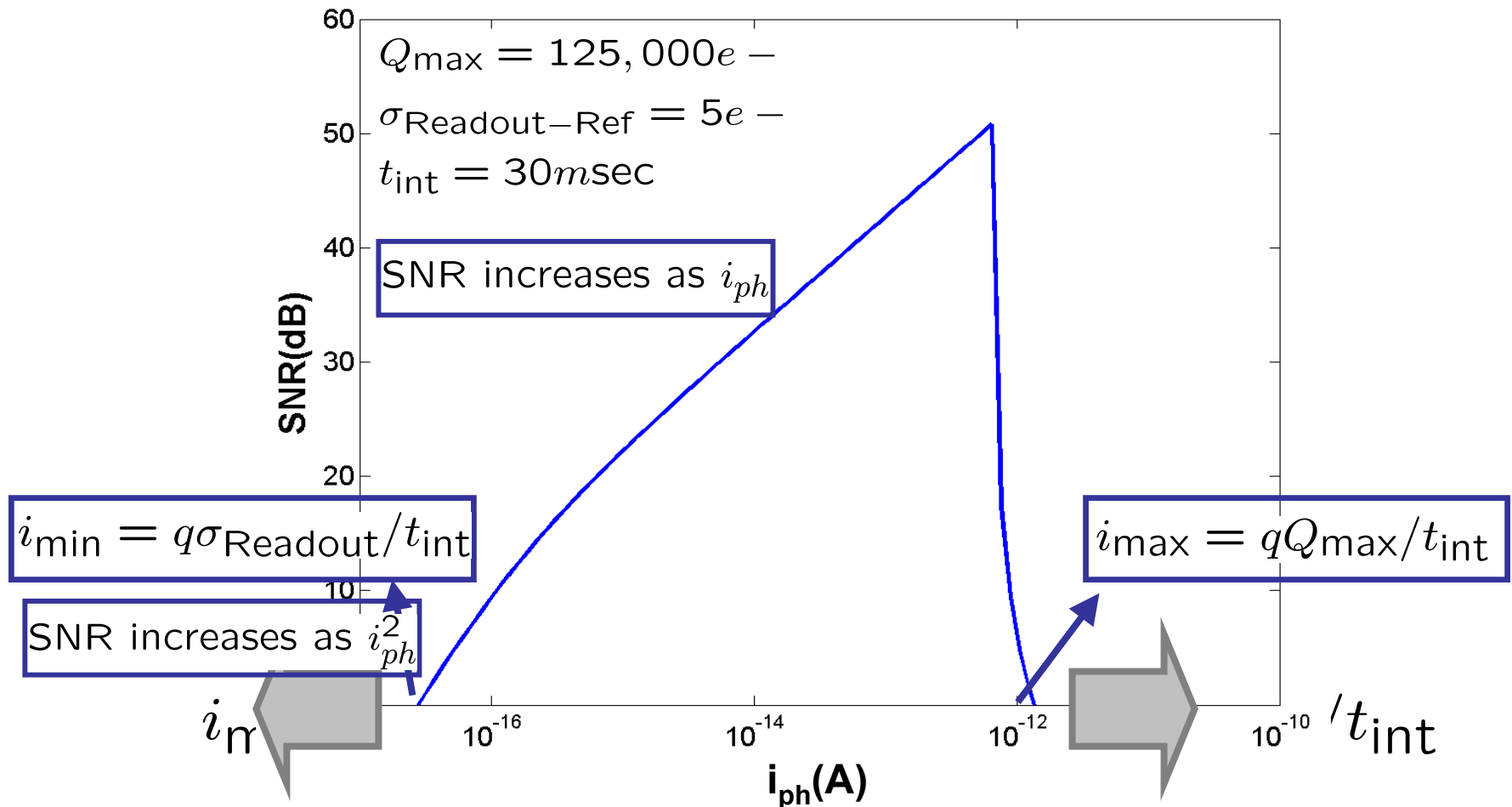
- Several methods have been developed to extend image sensor DR
- Deep submicron CMOS image sensor processes [Wuu '01] and vertical integration [Kozlowski '02] enable implementation of high DR, high fidelity methods
- This work studies four such schemes:
 - Time-to-saturation [Lule '99, Stoppa '02]
 - Multiple-capture [Yang '99, Kleinfelder '01, Bidermann '03]
 - Asynchronous self-reset with multiple capture [Liu '03]
 - Synchronous self-reset with residue readout [Bermak '02, Rhee '03]

SNR as Fidelity Measure

- How should these methods be compared?
- Methods can be partially compared based on their SNR [Yang '99, El Gamal '02]:
 - Some schemes extend DR but at expense of SNR
- This work:
 - Quantify SNR for the four schemes
 - Consider non-idealities due to implementation, especially due to pixel area constraint

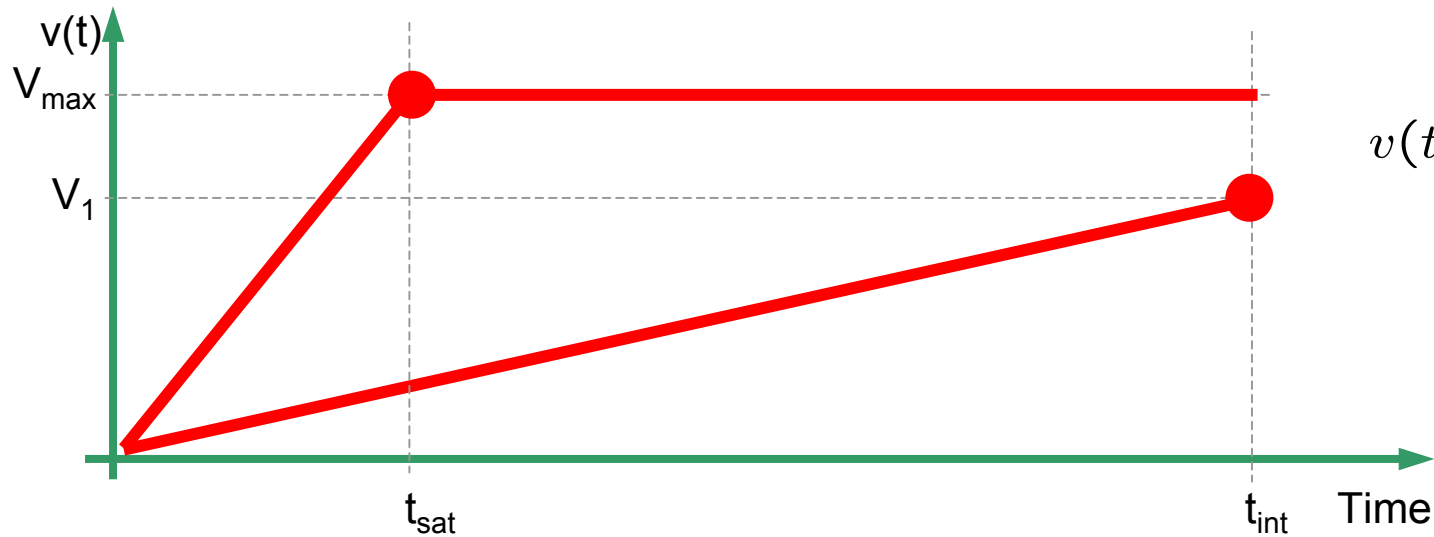
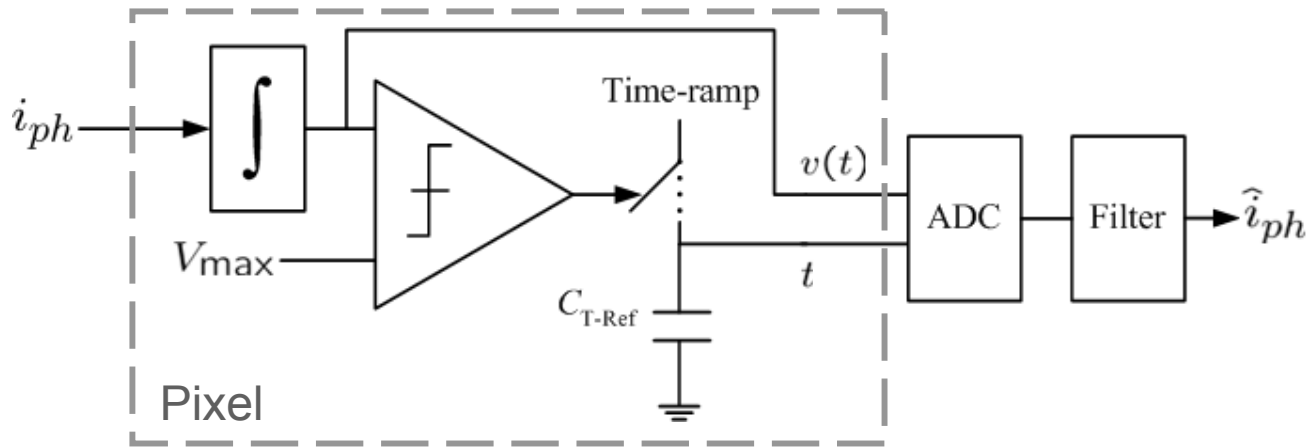
Conventional (Reference) Sensor

- CCD, APS, CTIA



Time-to-Saturation

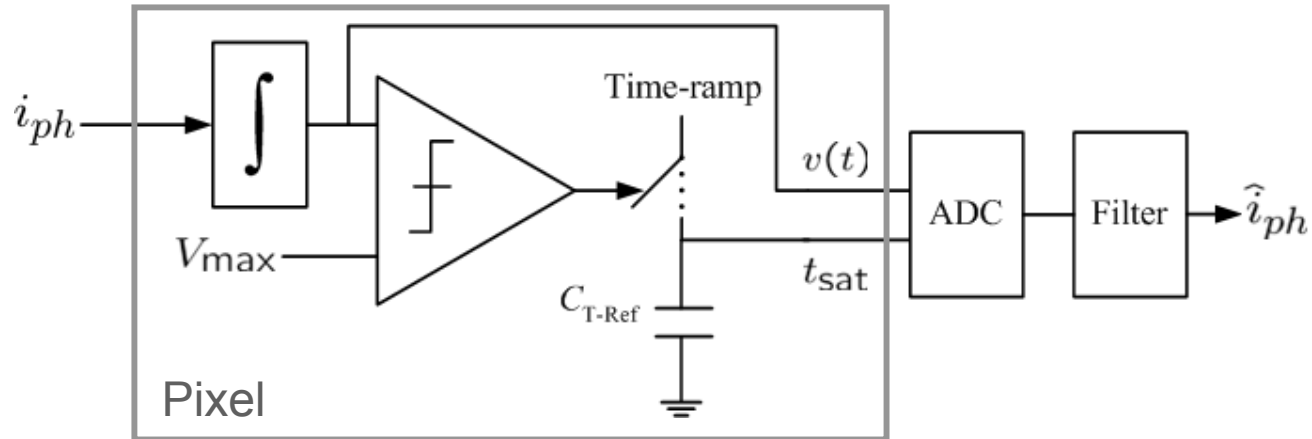
[Lule '99, Stoppa '02]



$$\begin{aligned}v(t_{int}) &= V_{max} \\ t &= t_{sat} \\ \hat{i}_{ph} &\propto V_{max}/t_{sat}\end{aligned}$$

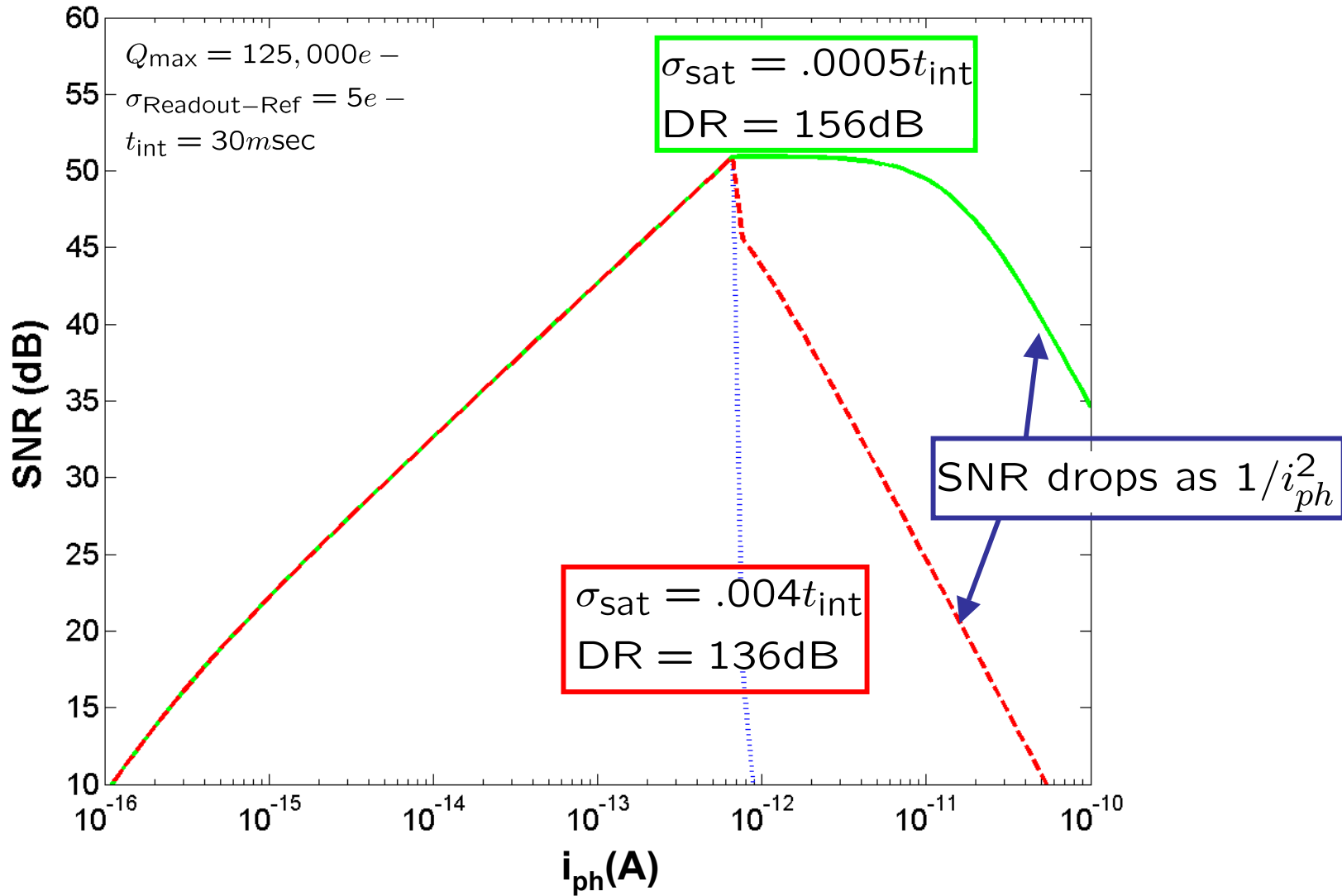
Time-to-Saturation

[Lule '99, Stoppa '02]



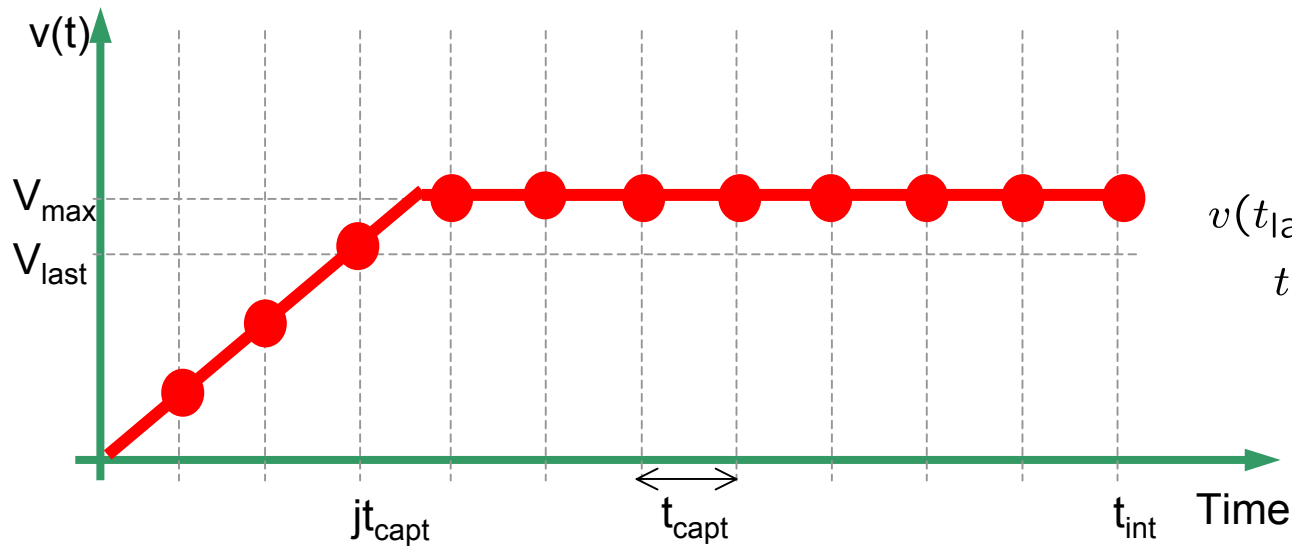
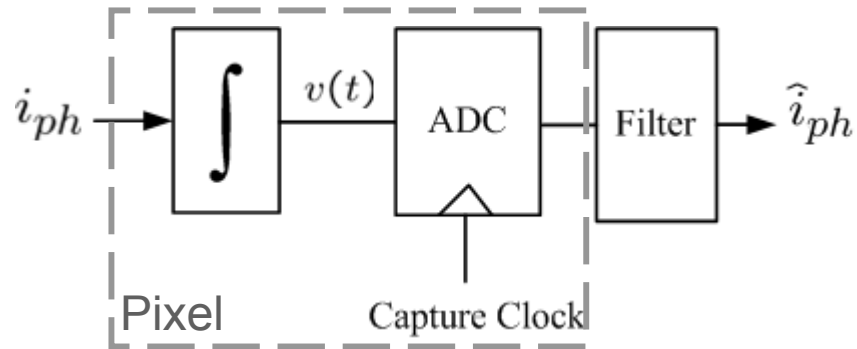
- $i_{min} = q\sigma_{Readout}/t_{int}$
 - ✓ Similar to reference sensor
- i_{max} and SNR limited by:
 - ✗ t_{sat} inaccuracy due to comparator noise/delay, time-ramp inaccuracy, kTC of C_{T-Ref} (inaccuracy in t_{sat} measured by σ_{sat})
- $i_{max} = qQ_{max}/\sigma_{sat}$

SNR



Multiple-Capture

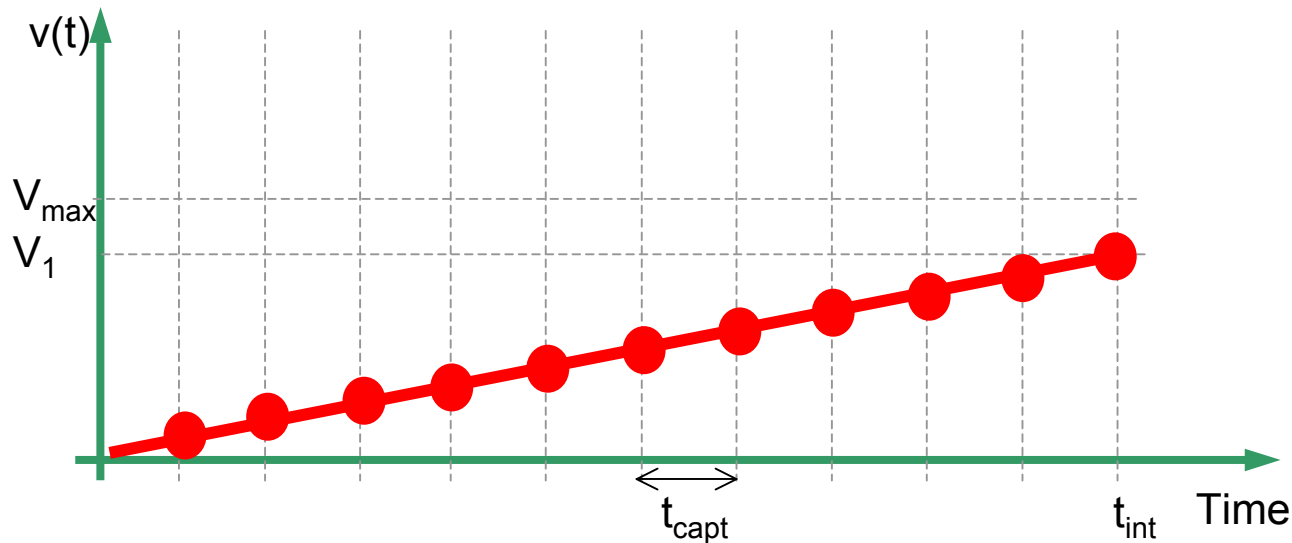
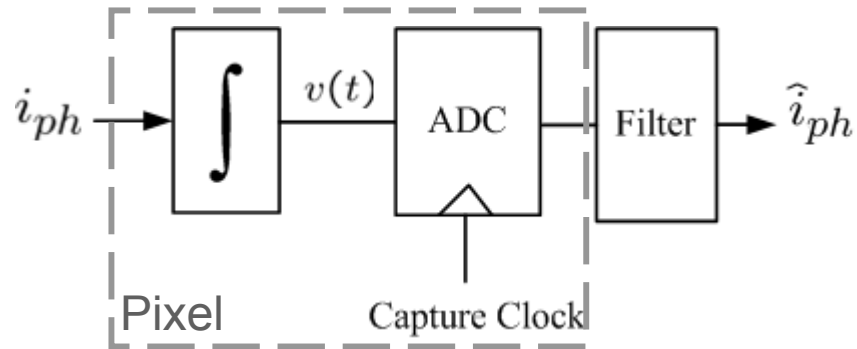
[Yang '99, Kleinfelder '01, Bidermann '03]



$$\begin{aligned} v(t_{last-sample}) &= V_{last} \\ t_{last-sample} &= jt_{capt} \\ \hat{i}_{ph} &\propto V_{last}/(jt_{capt}) \end{aligned}$$

Multiple-Capture

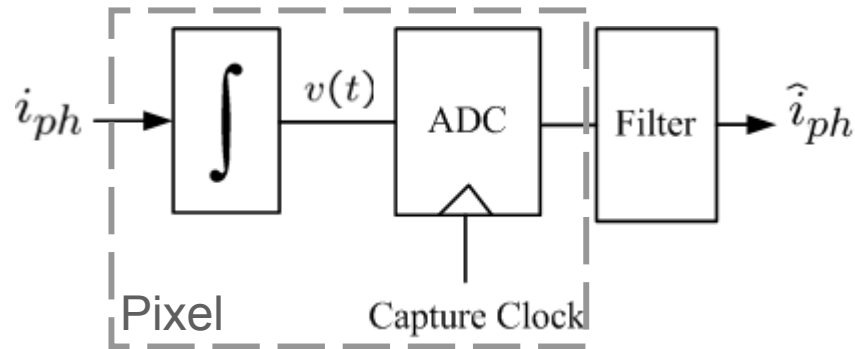
[Yang '99, Kleinfelder '01, Bidermann '03]



$$\begin{aligned}v(t_{\text{last-sample}}) &= V_1 \\t_{\text{last-sample}} &= t_{\text{int}} \\ \hat{i}_{ph} &\propto V_1/t_{\text{int}}\end{aligned}$$

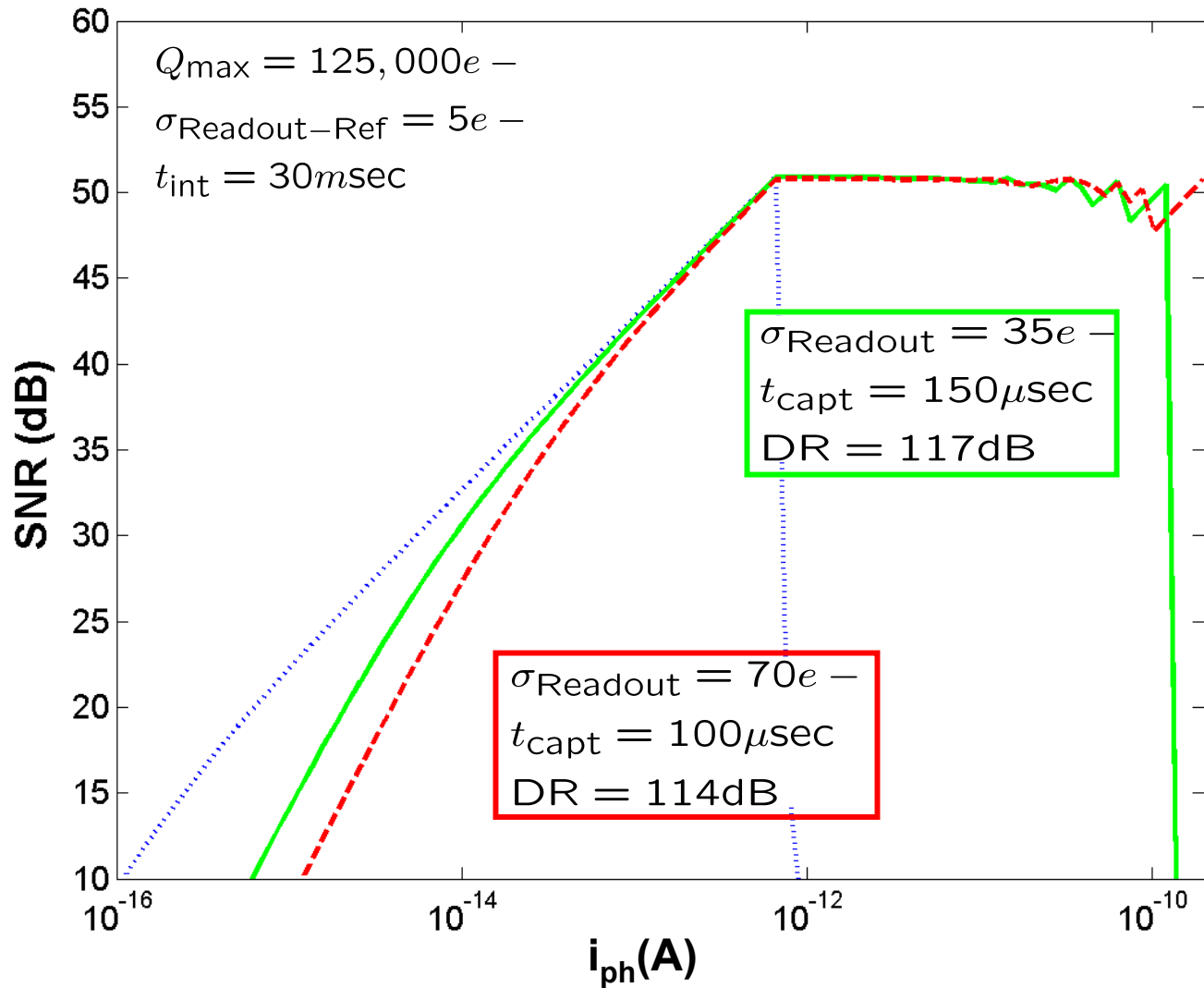
Multiple-Capture

[Yang '99, Kleinfelder '01, Bidermann '03]



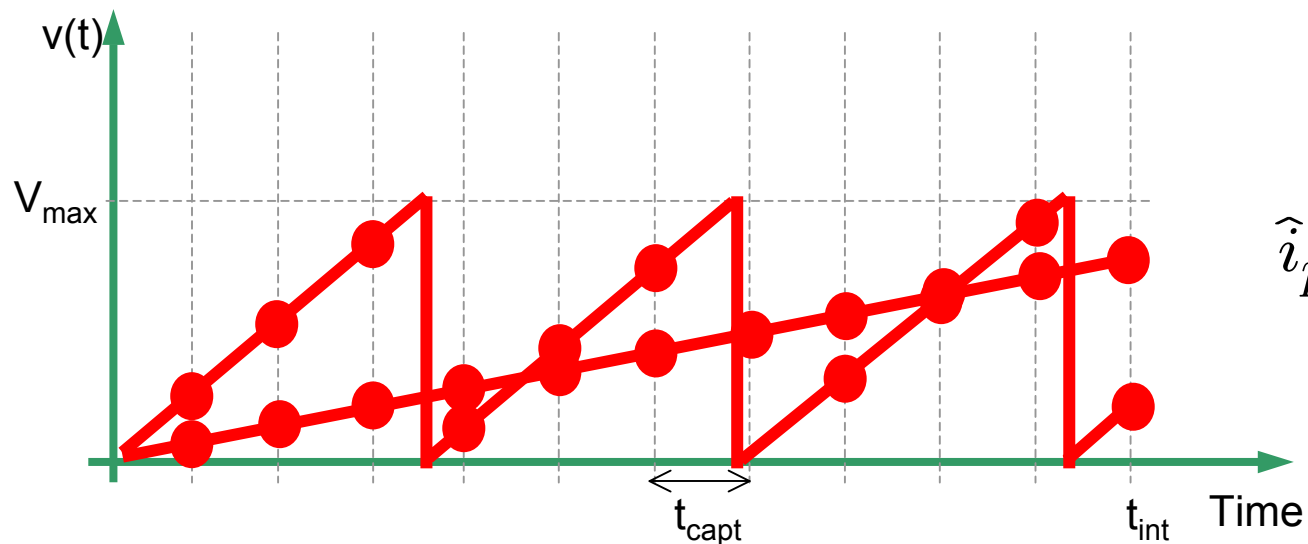
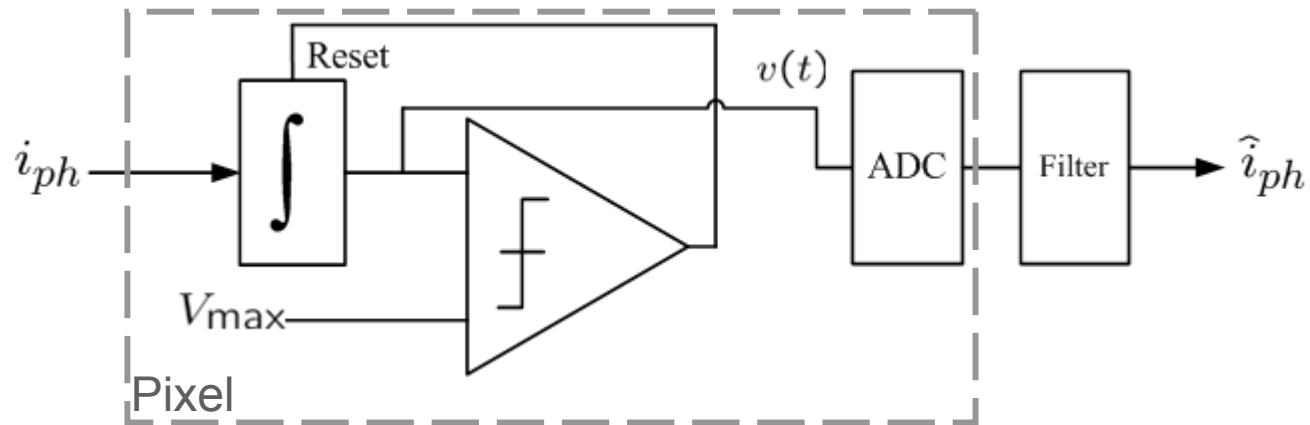
- $i_{\min} = q\sigma_{\text{Readout}}/t_{\text{int}}$
 - ✗ Pixel-level ADC resolution limited (ADC-ramp, speed/resolution trade-off)
 - ✓ Digital weighted averaging is possible [Liu '03]
 - ✓ Increasing t_{int} is possible by motion blur prevention [Liu '03]
- $i_{\max} = qQ_{\max}/t_{\text{capt}}$
 - ✓ Capture time is very accurate

SNR



Asynchronous Self-Reset

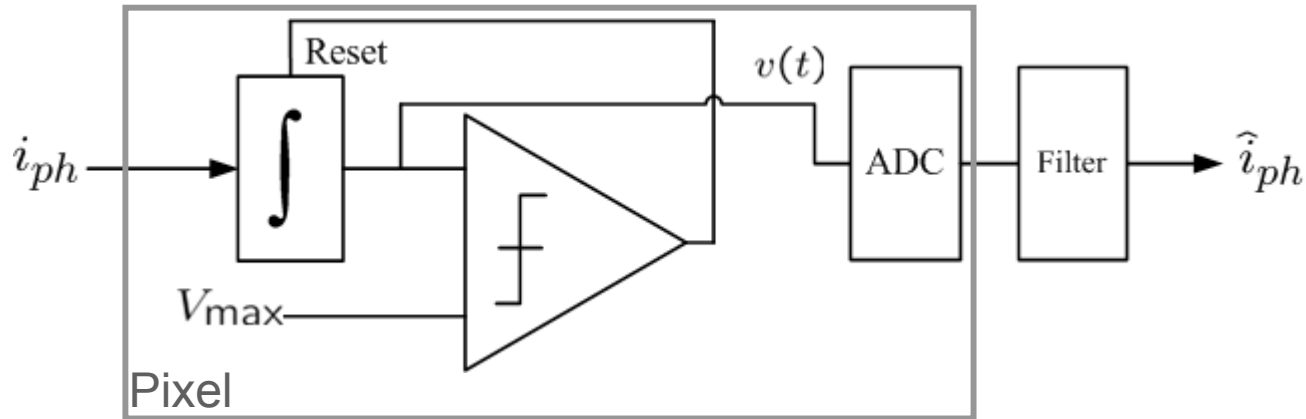
[Liu '02]



$$\hat{i}_{ph} \propto v'(t)$$

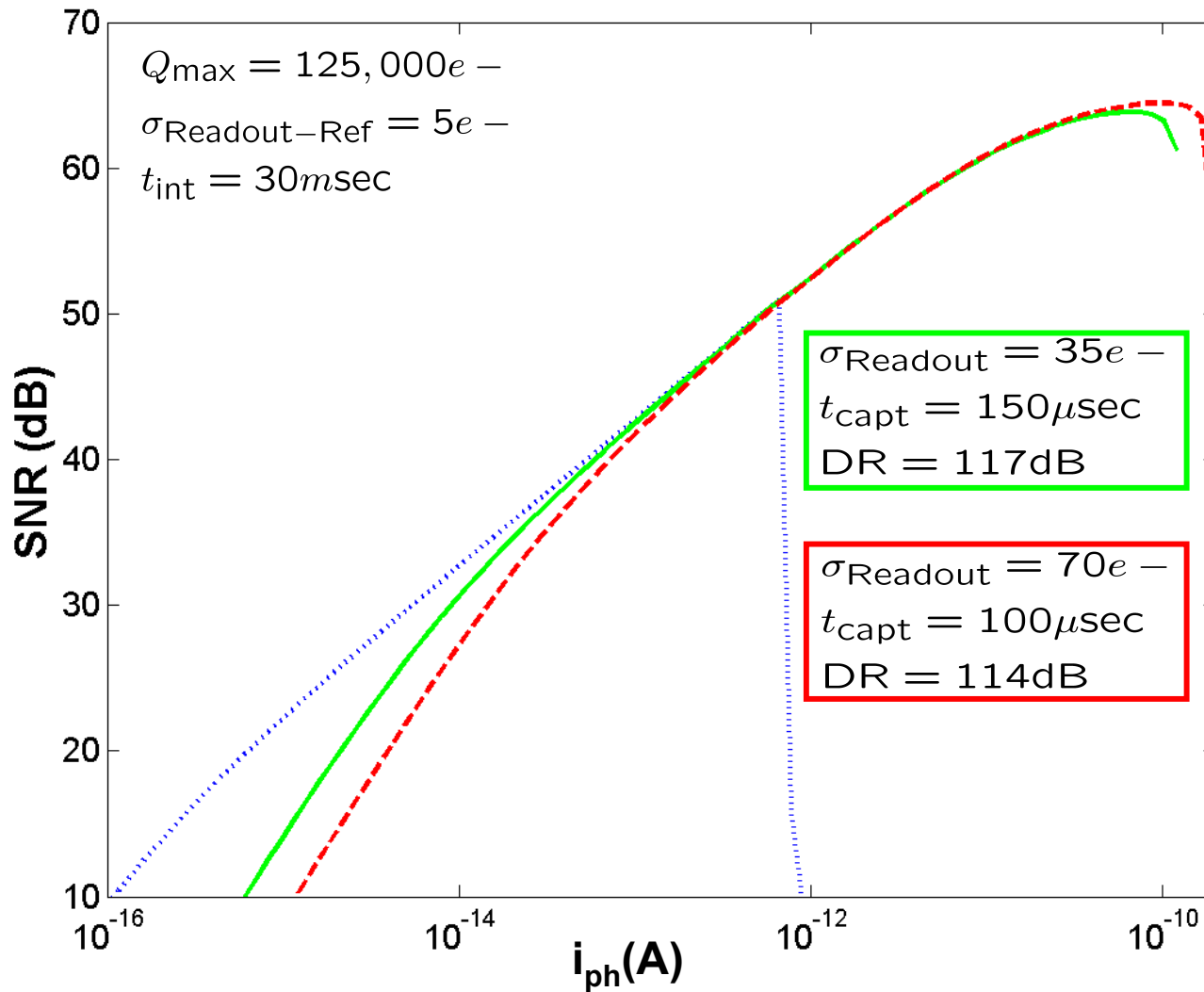
Asynchronous Self-Reset

[Liu '02]



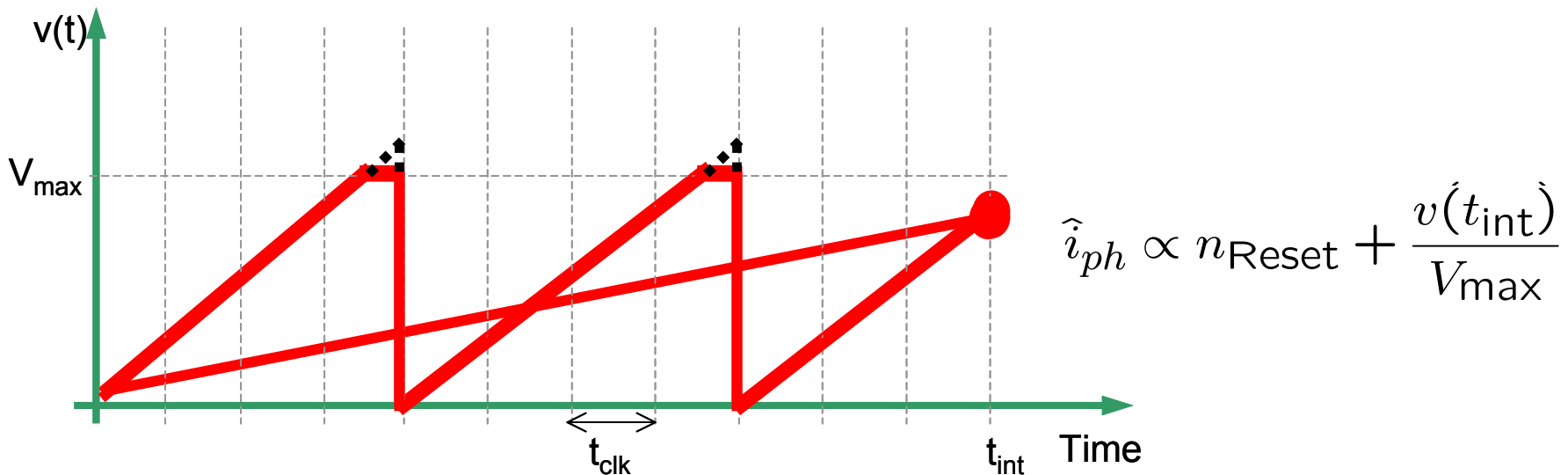
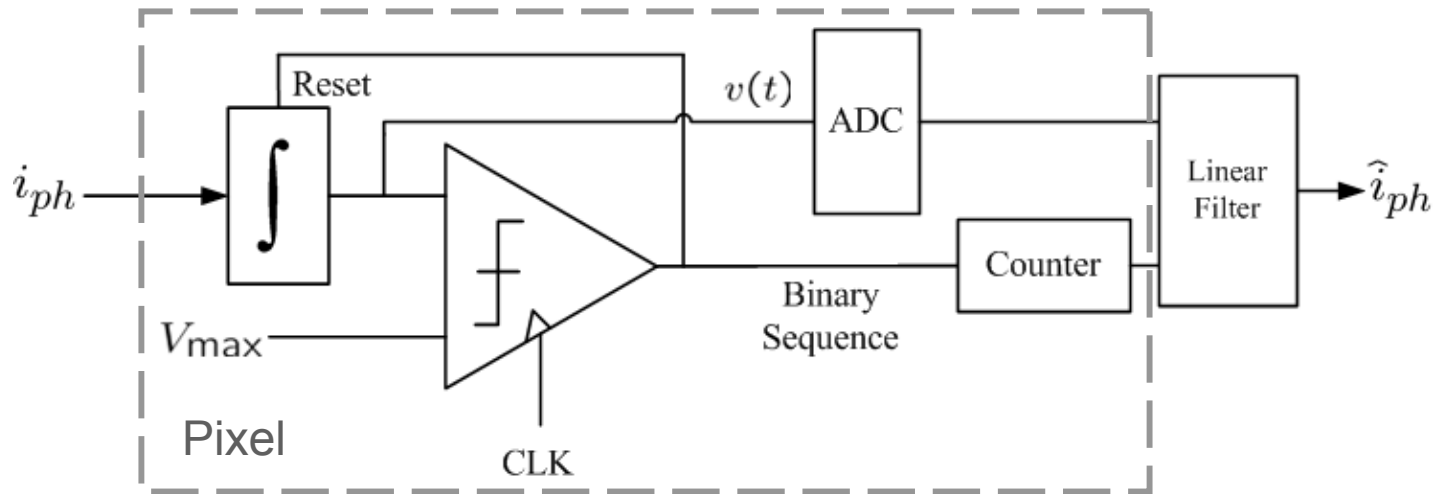
- $i_{min} = q\sigma_{Readout}/t_{int}$
- $i_{max} = qQ_{max}/t_{capt}$
- SNR better than MC but with higher DSP cost:
 - ✗ ADC resolution limited (ADC-ramp, speed/resolution trade-off)
 - ✓ Digital weighted averaging can compensate for it
 - ✓ Increasing t_{int} is possible by motion blur prevention [Liu '03]
 - ✓ Self-reset accuracy is relaxed
- SNR increasing but limited by gain FPN

SNR



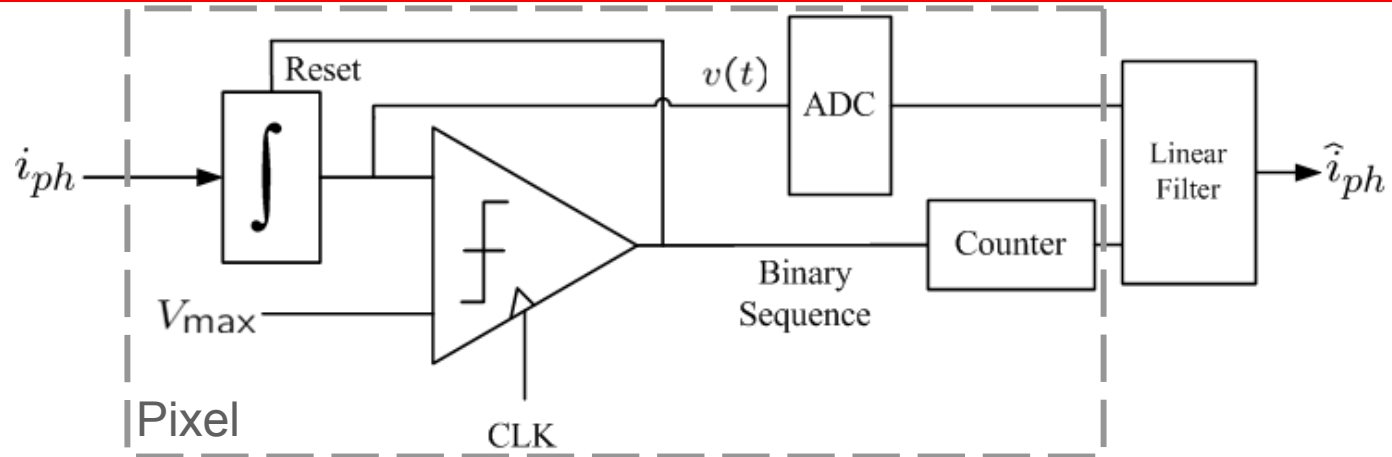
Synchronous Self-Reset with Residue Readout

[Bermak '02, Rhee '03]



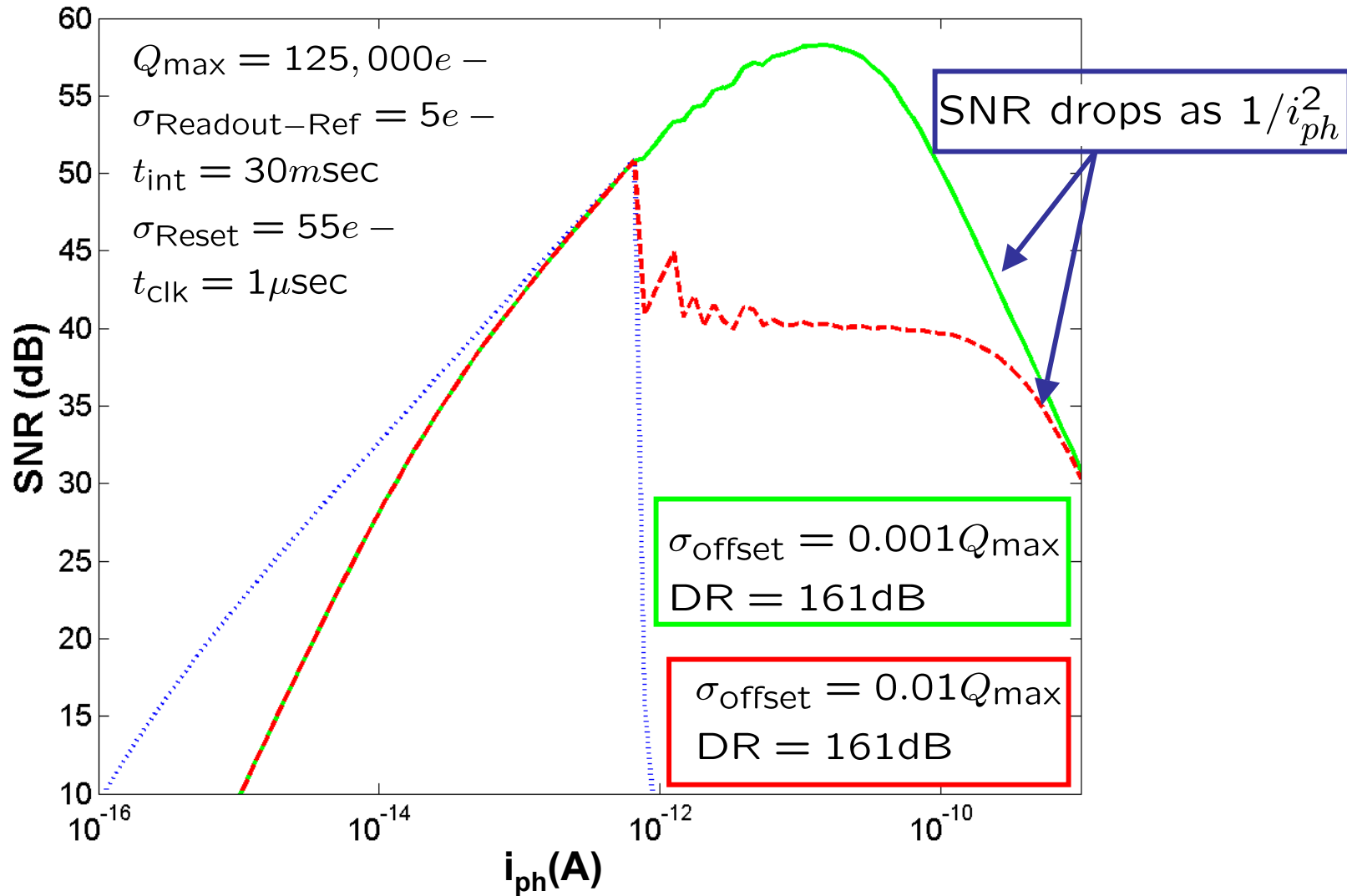
Synchronous Self-Reset with Residue Readout

[Bermak '02, Rhee '03]



- $i_{min} = q\sqrt{\sigma_{Readout}^2 + \sigma_{Reset}^2/t_{int}}$
 - ✗ Reset noise and ADC resolution
- i_{max} and SNR at high end limited by:
 - ✗ Comparator and self-reset offset accumulation resulting in gain FPN (inaccuracy measured by σ_{offset})
 - ✗ Underestimation of i_{ph} due to signal saturation
- $i_{max} = \sqrt{3}qQ_{max}/t_{CLK}$

SNR



Summary

Method	i_{\min}	i_{\max}	SNR	Pixel Mismatches Effect	DSP	Power
TTS	=	++	-	High	Low	Comparator
MC	- /=	+	+	Moderate	Moderate	Readout/DSP
Async	- /=	+	++	Moderate	High	Readout/DSP
Sync	--	+++	--	High	Moderate	Comparator/digital circuits